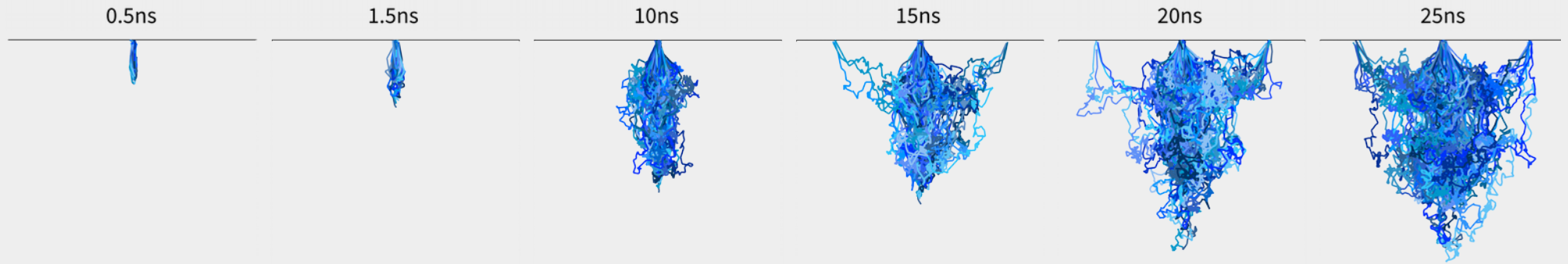




cern.ch/allpix-squared



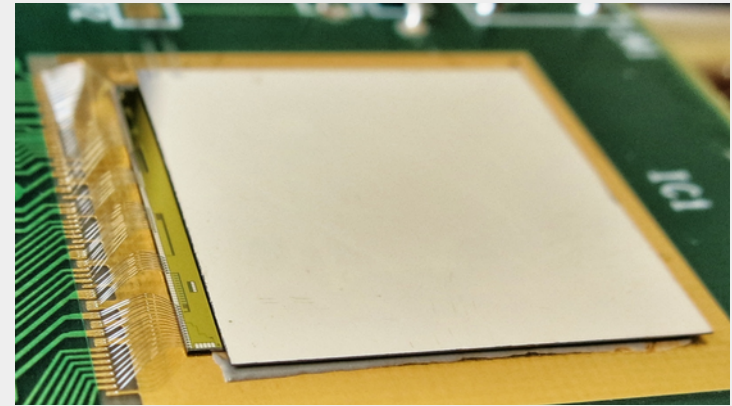
The Importance of Insight

Monte Carlo Simulations in Silicon Pixel Detector Development

Simon Spannagel, CERN
DESY Instrumentation Seminar
9 August 2019

Silicon Pixel Detectors in High Energy Physics

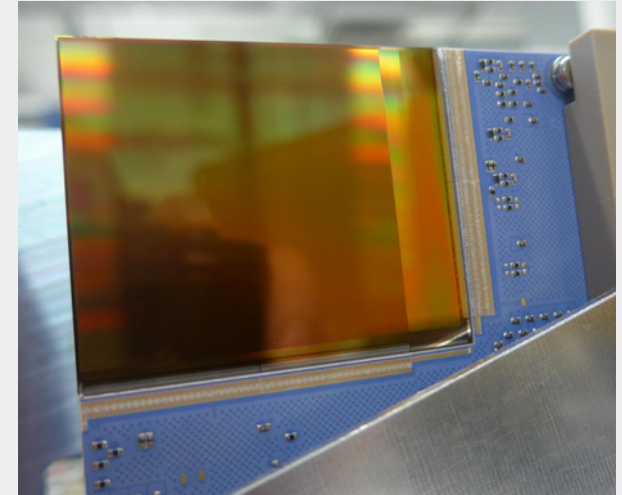
- Crucial in today's experiments: primary/secondary vertex resolution, pile-up reduction
- Demands on detectors are high:
 - Maximum resolution @ minimum (scattering-) mass
 - Very high granularity for high particle rates, fast readout, minimal dead time
 - “Smart” detectors (zero suppression, clustering, on-chip processing)
- Initially, HEP was innovation driver
- Understanding technologies, behavior with radiation etc. known technologies
- Lately: catching up to more recent (imaging!) technologies used in industry – interesting features, but complex designs



100 μm Timepix with 100 μm Sensor

Silicon Pixel Detectors in Photon Science

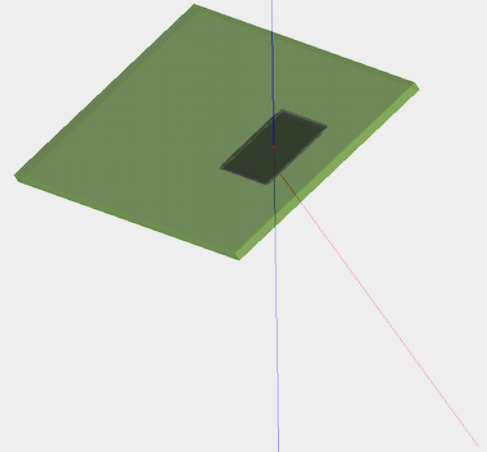
- Demands are different – but equally challenging
 - Large area imaging sensors
 - High frame rate at very low noise
 - Single photon sensitivity plus large dynamic range
- High-Z materials of interest
 - Much smaller absorption length for 1-100 keV photons
 - Not as many models for sensor response around as for silicon
- Overlap with HEP in sensor technology used, difference e.g. in material budget
- Similar challenges in designing detectors in new deep sub-micron CMOS



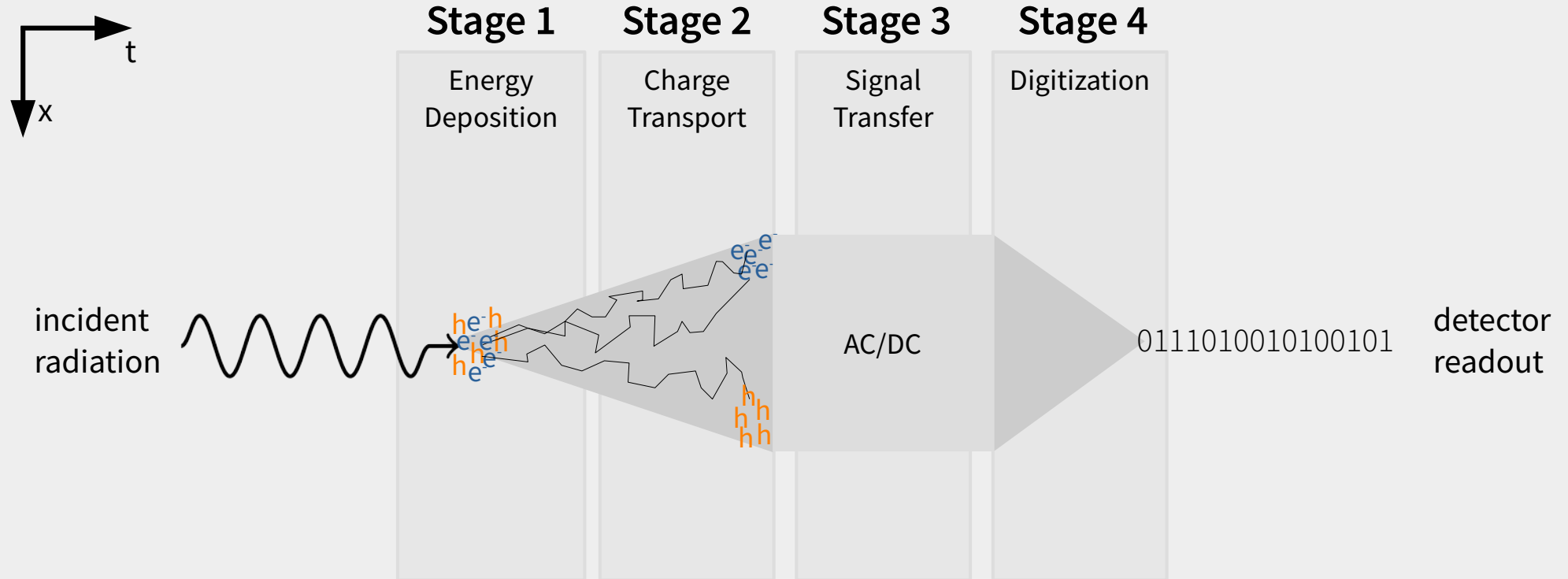
Percival

Introduction

Particle Detection with Silicon Detectors

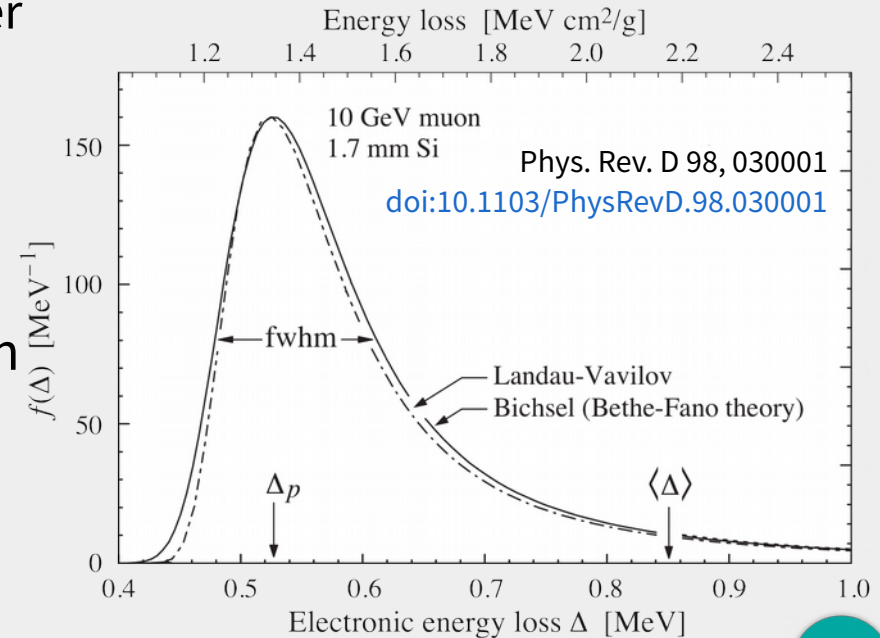


Recap: Particle Detection with Silicon Detectors



Stage 1 – Energy Deposition

- (heavy) charged particles:
Mean energy loss described by **Bethe Bloch** formula
- Strong fluctuations of energy loss: **Landau-Vavilov** distribution / **Bichsel** model
 - Varying number interactions, energy transfer
 - Secondary particles (e.g. delta rays)
 - Most probable value < Mean
- Photons:
Photo effect, Compton effect, pair production
- Creation of e/h pairs: 3.64 eV / pair
Fluctuations: **Fano** Factor $\sigma_{e/h} = \sqrt{N_{e/h}} \sqrt{F}$



Stage 2 – Signal Formation

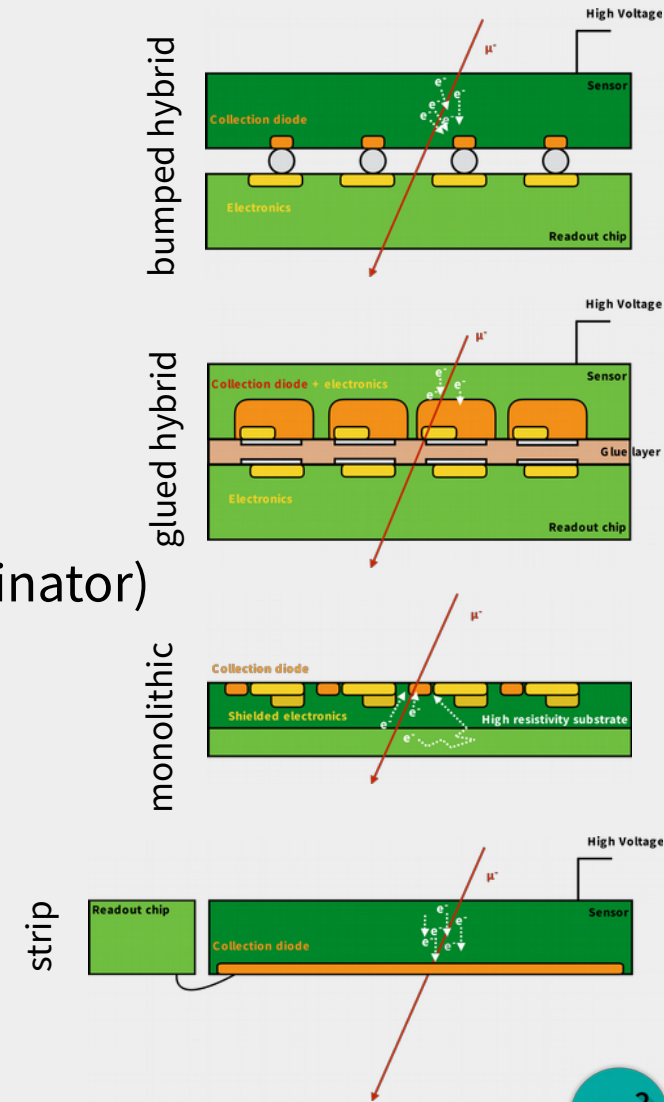
- Si sensor operated as diode in reverse bias → depleted volume
- Signal formed by motion of e/h pairs in electric field
- Contribution to motion:
 - **Diffusion** – Temperature-driven random motion, mean free path $\sim 0.1 \mu\text{m}$, mean 0
 - **Drift** – Directed motion, depending on electric field and charge carrier mobility, different parametrizations for mobility available, depending on temperature, silicon, ...
- Motion stops, when...
 - Charge carriers reach readout electrode (conductor)
 - Charge carriers recombine/get trapped (depends on purity, doping, lattice defects, ...)
- When carriers reach electrodes, total induced charge is equivalent to collected charge

Stage 3 – Signal Transfer

- Coupling between sensor & front-end can be
 - DC: bump bonds (hybrid pixel), direct (monolithic pixel)
 - AC: glue layers (hybrid pixel), SiO₂ (strip detectors)

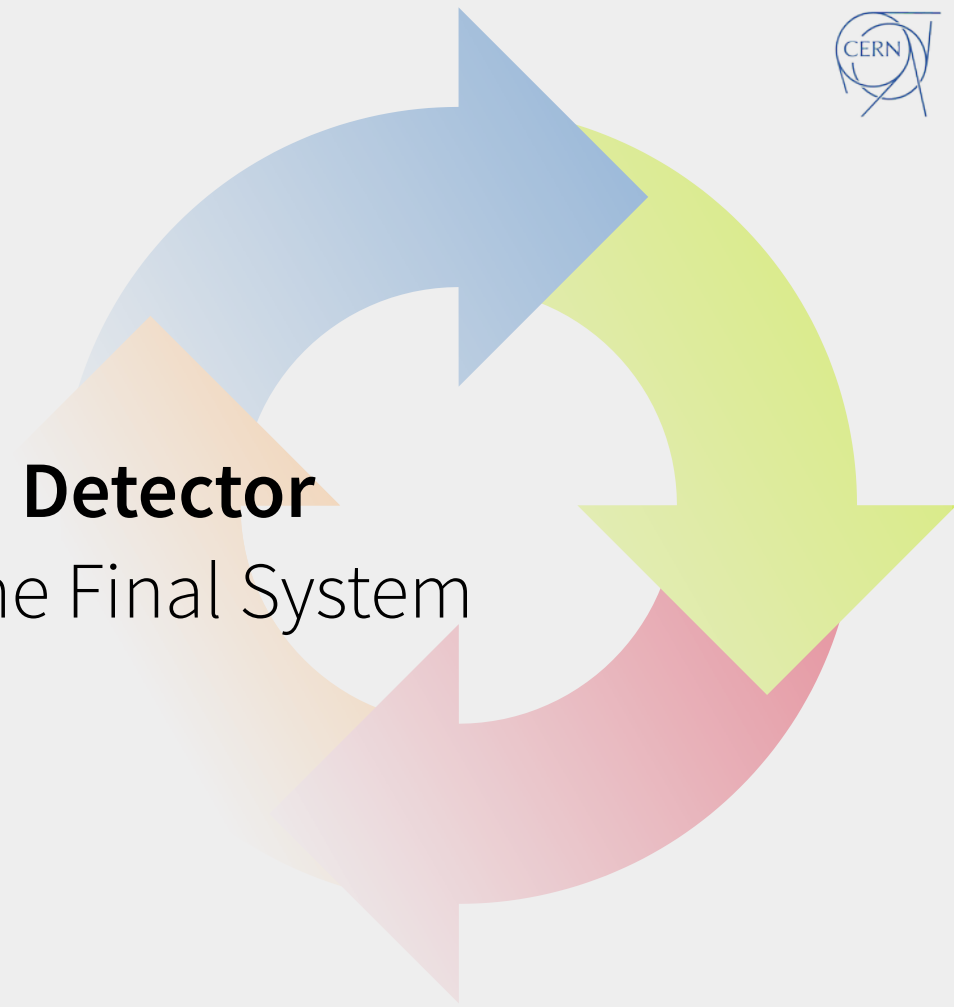
Stage 4 – Digitization

- Signal is amplified, shaped, zero-suppression (discriminator)
- Digitization of the signal via
 - Full ADC
 - Time-over -threshold
 - Threshold crossing (binary hit information)
- Buffering, encoding, data transmission...

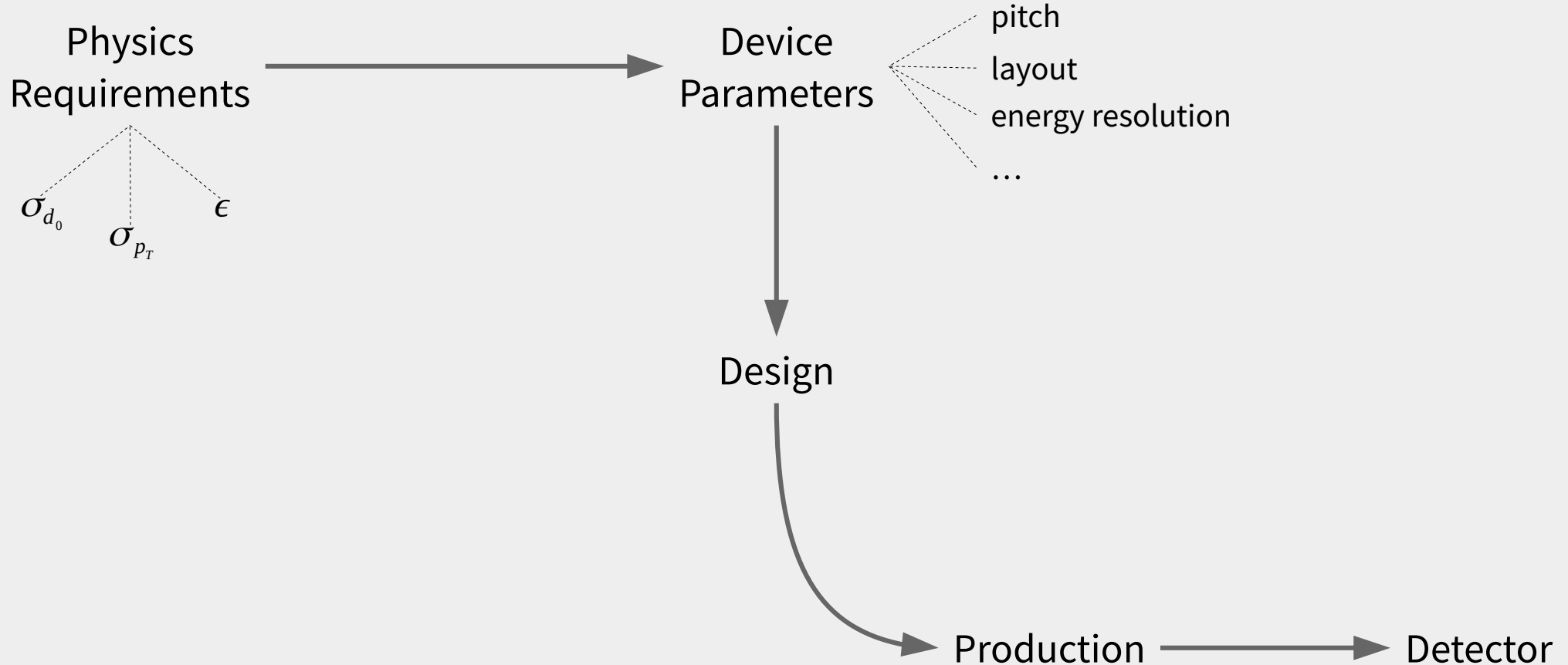


Development Cycle of a Silicon Detector

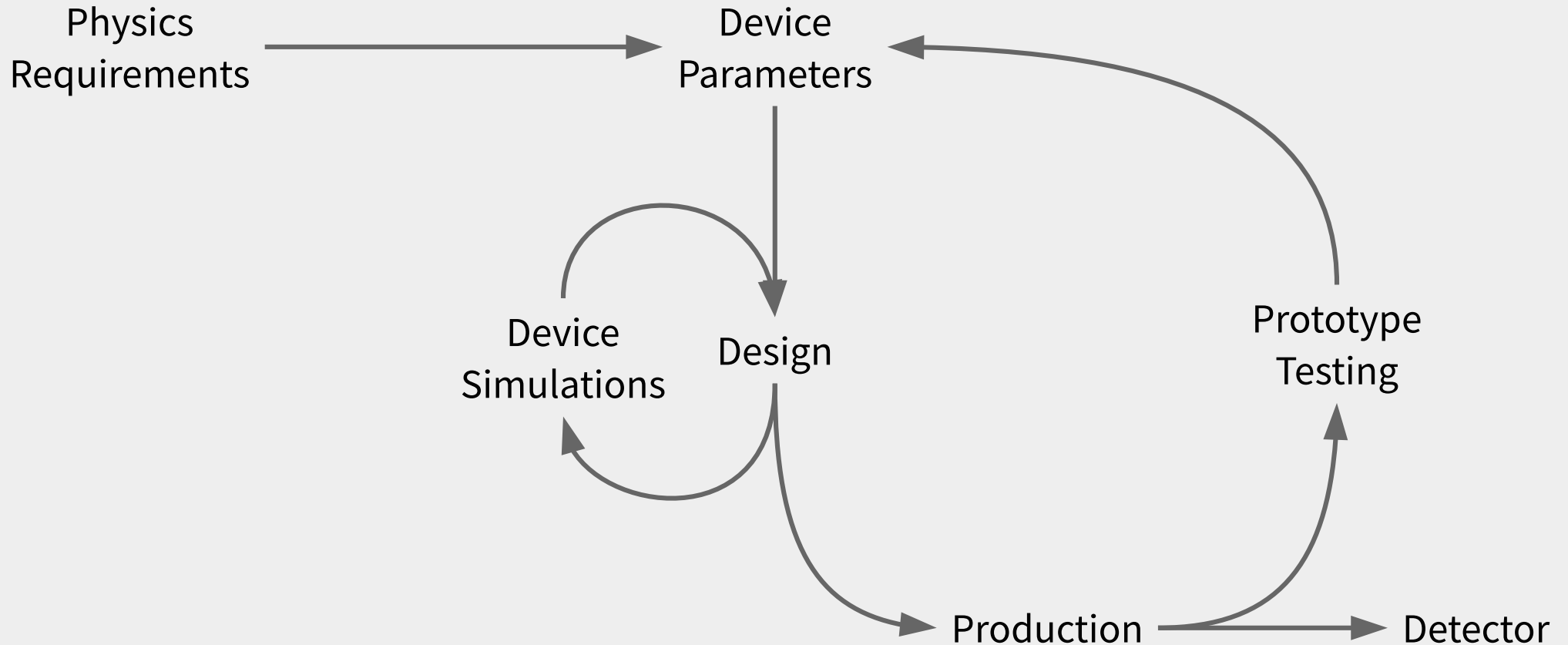
From Physics Requirements to the Final System



Development Cycle of a Silicon Detector

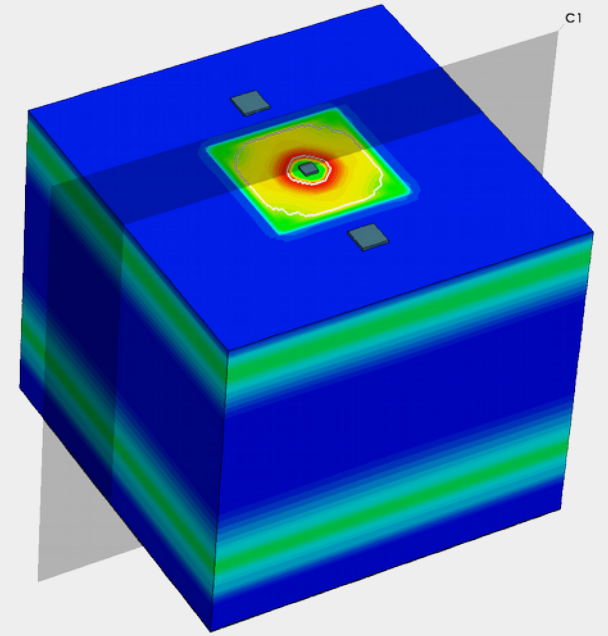


Development Cycle of a Silicon Detector



TCAD Sensor Simulations

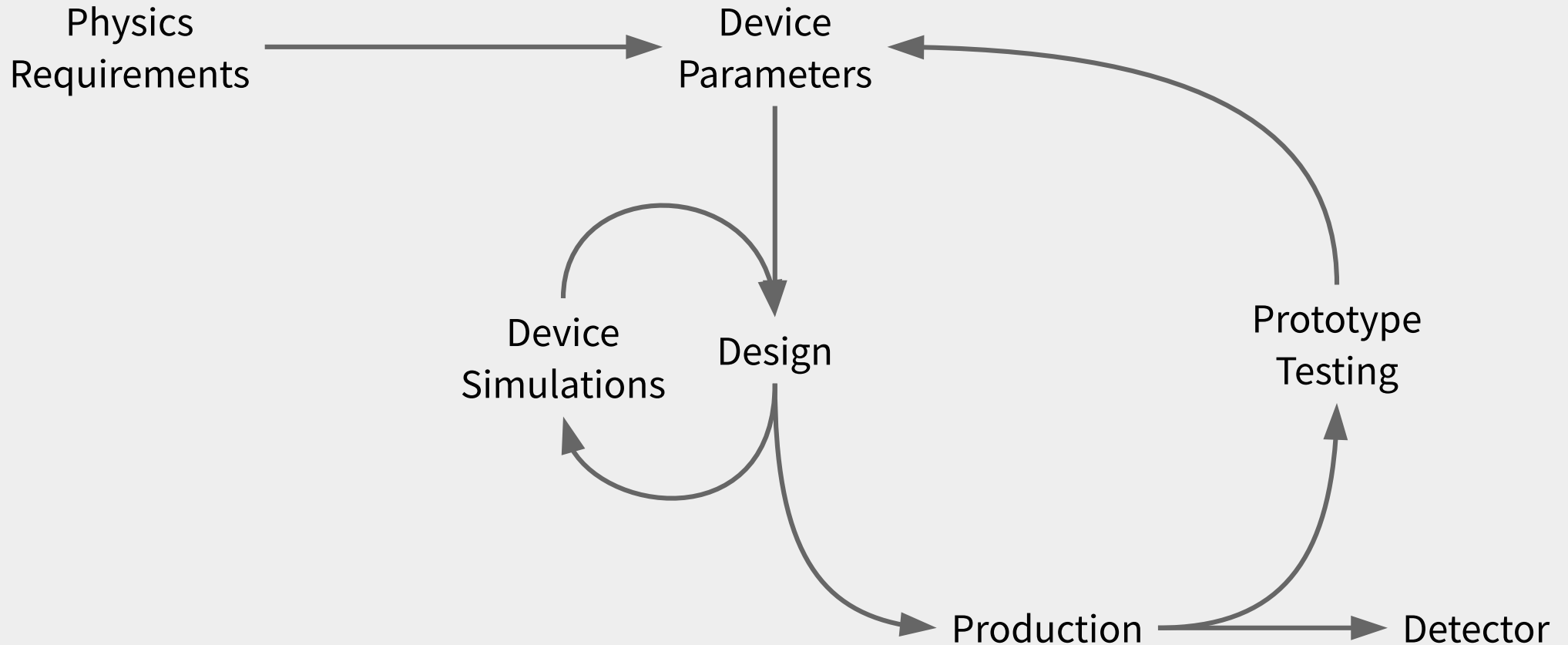
- *Technology Computer Aided Design*
 - Simulate electrical properties of semiconductor by numerically solving field equations on mesh
- Requires knowledge of the production process (doping concentrations, implants)
- Provide detailed information on
 - Field configuration of the device
 - Derived parameters: depletion voltage, break down voltage
- Also allows to perform time-resolved transient simulations: current pulses
 - Very time consuming, especially in 3D
 - Periodic boundary conditions might allow to reduce complexity



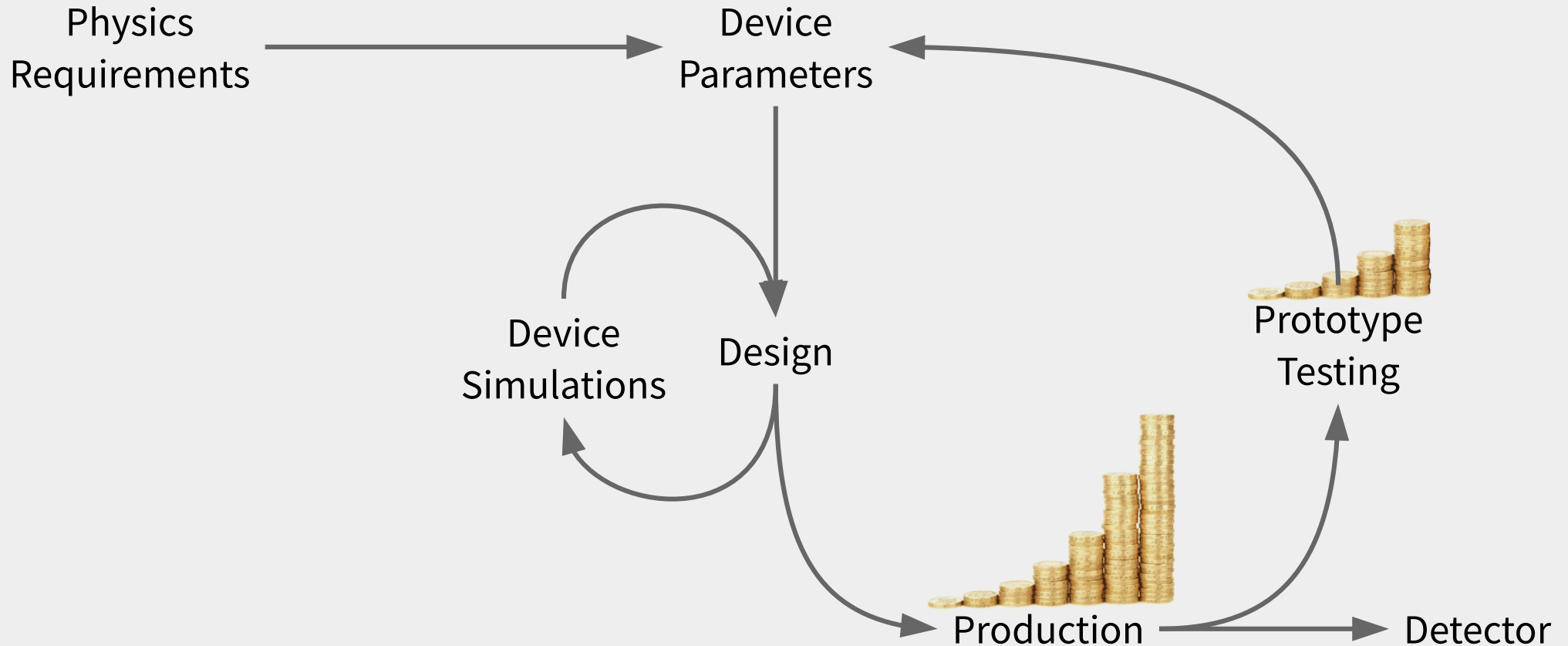
Front-End Circuit Simulation

- SPICE – *Simulation Program with Integrated Circuit Emphasis*
 - Simulate response of circuit to external stimuli
 - Many commercial derivatives, usually come with EDA software
- Based on IC design, either schematics or on netlist level
- Provides detailed information on
 - Response of front-end amplifier
 - Digitization process
- Works on individual input pulses
 - Time-consuming
 - Not really feasible to repeat for large number of input pulses

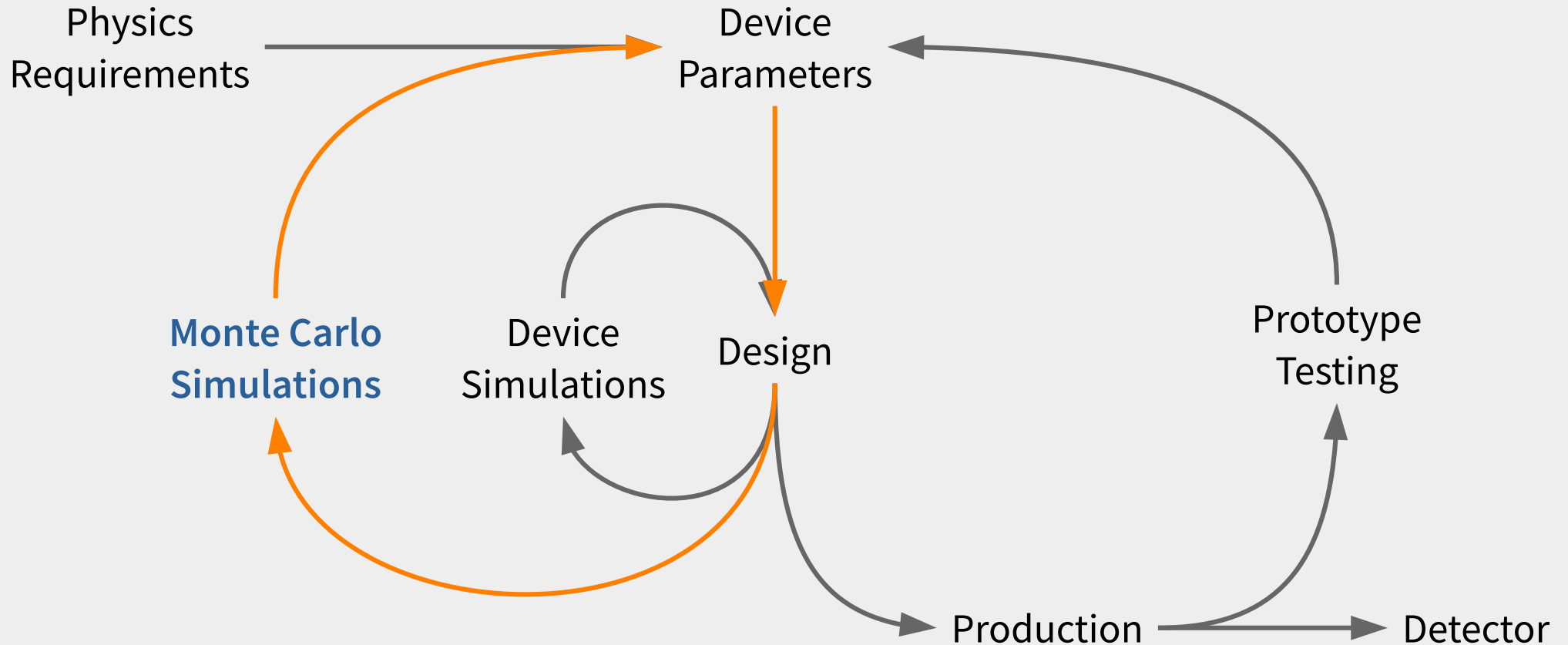
Development Cycle of a Silicon Detector



Development Cycle of a Silicon Detector

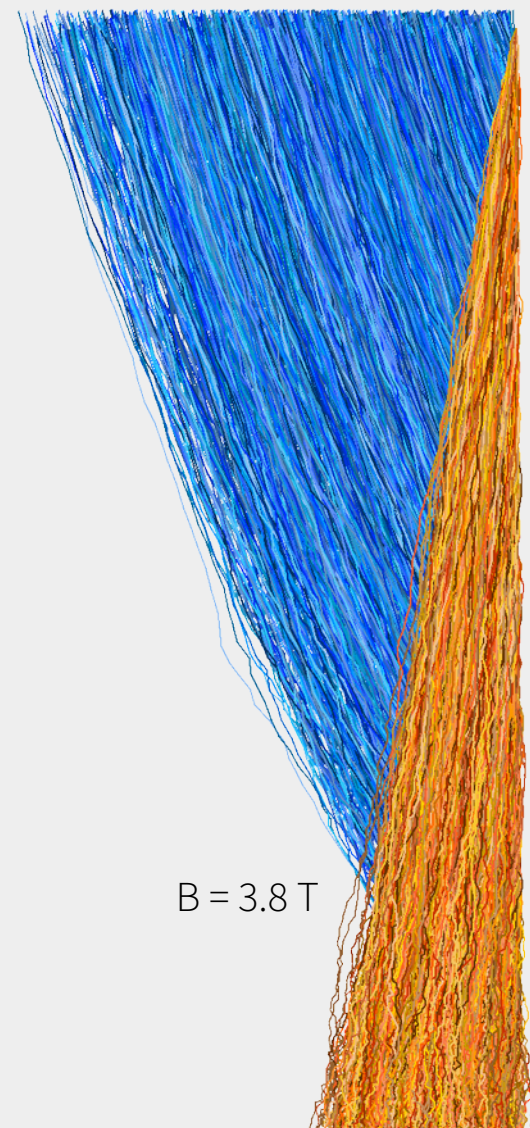


Development Cycle of a Silicon Detector



Monte Carlo Simulations

Access to Performance Parameters



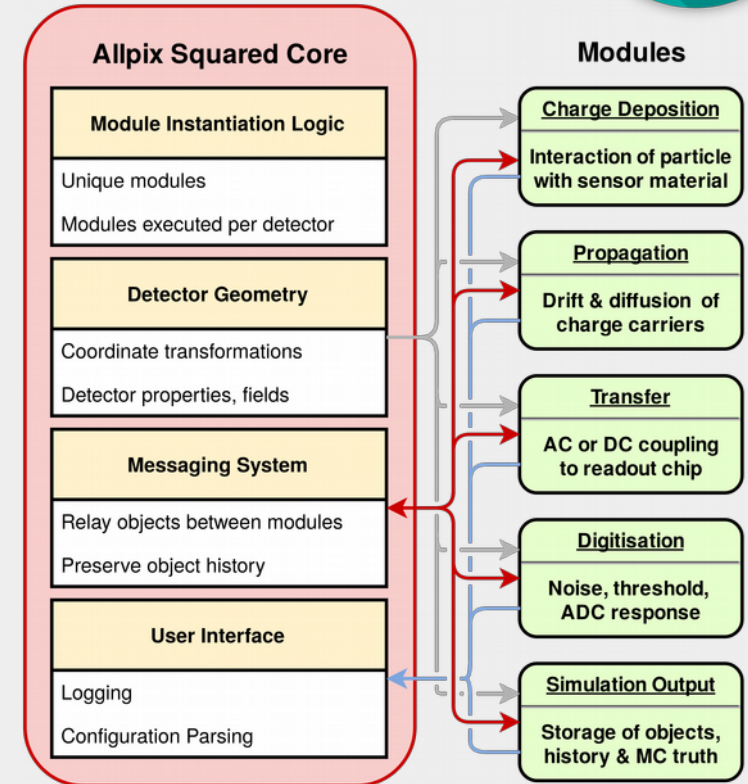
Monte Carlo Simulations

- Simulate full chain: energy deposition → readout
- Include **stochastic effects, fluctuations, secondaries**
- Requires **simplifications**:
 - No self-interaction, static electric field, ...
 - Empirical models for different stages
- Allows to derive **performance parameters**
 - Position resolution, timing, efficiency
 - Combine with results from device simulations to increase accuracy
- Monte Carlo Simulation Codes:
AllPix, PixelAV, KdetSim, Garfield++, (unpublished codes), ..., **Allpix Squared**

The Allpix² Framework

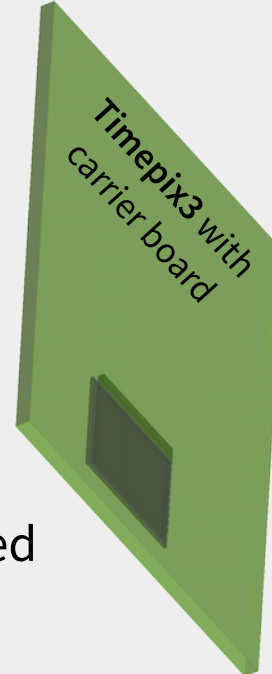


- Flexible MC simulation software, that
 - ...allows to **test different simulation models for signal formation**
 - ...implements parametrized detector models
 - ...facilitates usage of **precise electric fields**
- Focus on usability
 - Separate infrastructure from physics
 - Easy setup & configuration
 - Provide documentation (150p. [user manual](#))
- Developed within **CLICdp collaboration**



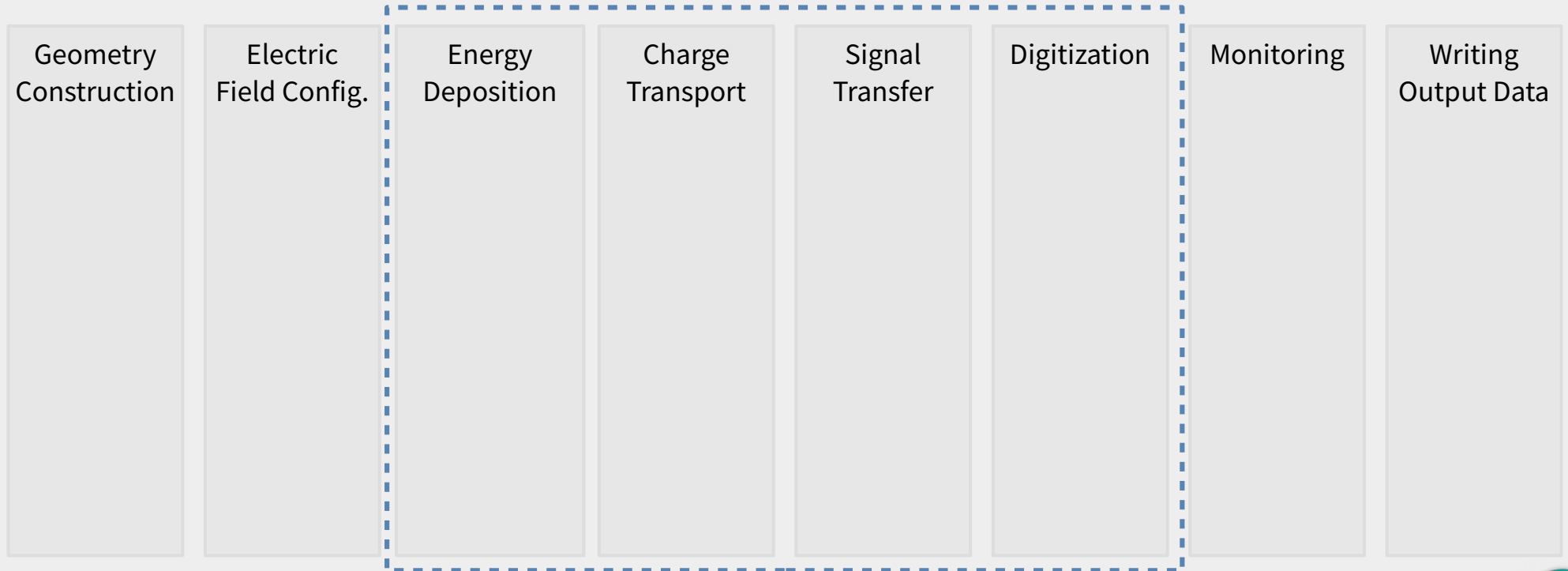
Configuration of the Simulation Chain

- Building simulation chain from individual modules
 - Configuration file with modules in order of execution
 - Support for physical units
- Every parameter documented in manual
- Geometry configuration
 - File with position/orientation of individual detectors
 - Model files define detector geometries
 - Different detector models pre-configured



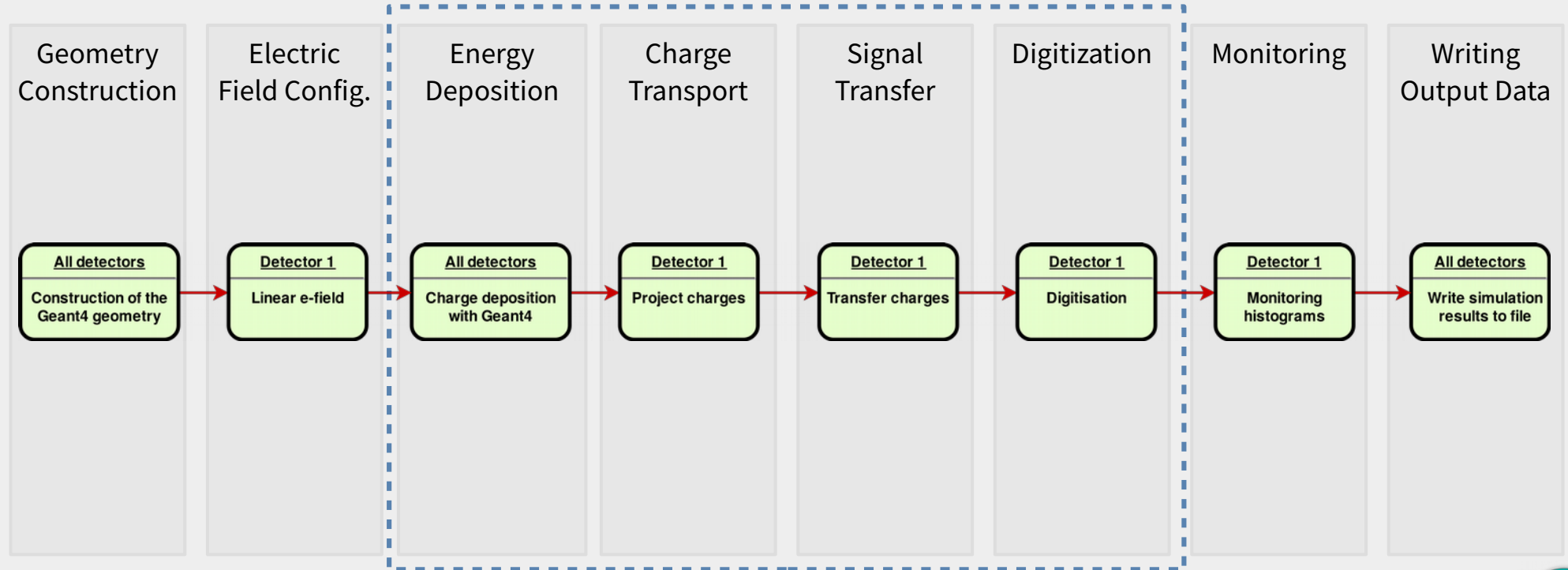
```
1 [AllPix]
2 log_level = "INFO"
3 number_of_events = 500000
4 detectors_file = "telescope.conf"
5
6 [GeometryBuilderGeant4]
7 world_material = "air"
8
9 [DepositionGeant4]
10 physics_list = FTFP_BERT_LIV
11 particle_type = "Pi+"
12 number_of_particles = 1
13 beam_energy = 120GeV
14 # ...
15
16 [ElectricFieldReader]
17 model="linear"
18 bias_voltage=150V
19 depletion_voltage=50V
20
21 [GenericPropagation]
22 temperature = 293K
23 charge_per_step = 10
24 spatial_precision = 0.0025um
25 timestep_max = 0.5ns
26
27 [SimpleTransfer]
```

The Simulation Chain



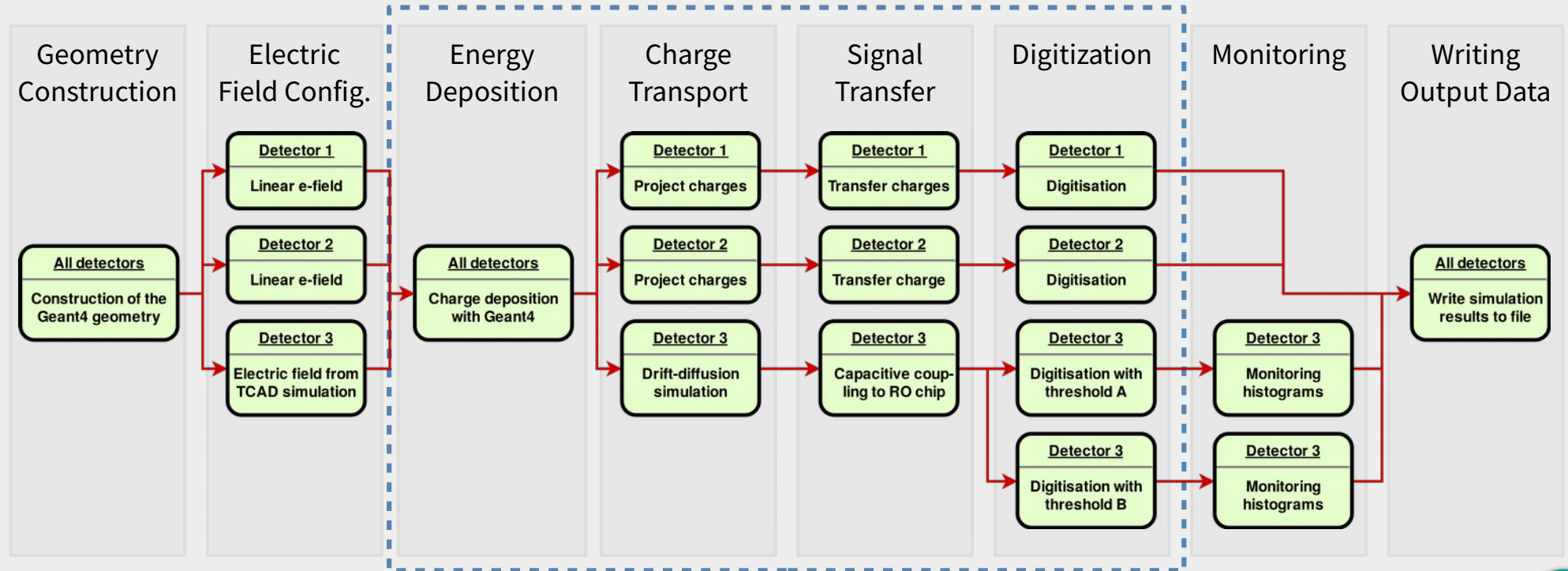
The Simulation Chain

- Building blocks follow individual steps of signal formation in detector
- Algorithms for each step can be chosen independently



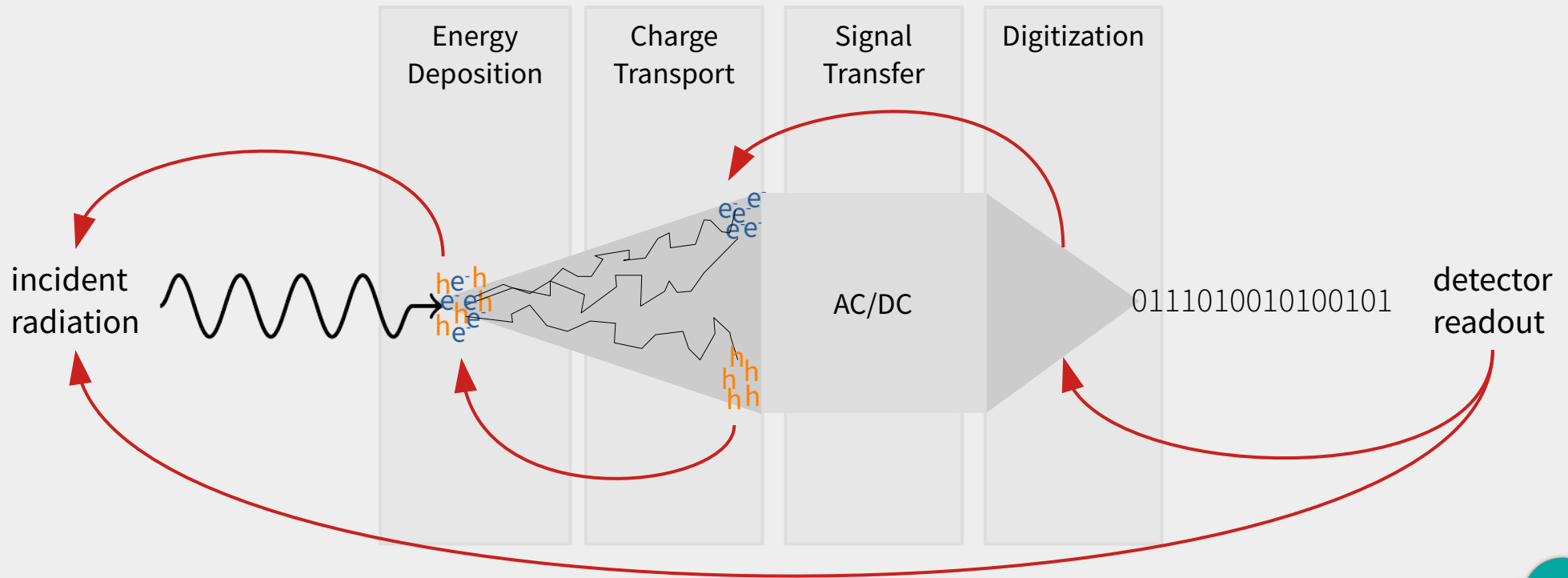
The Simulation Chain

- Simulation very flexible: modules configurable on per-detector level
- Multiple instances can be run in parallel (e.g. to simulate different front-ends)



The Monte Carlo Truth

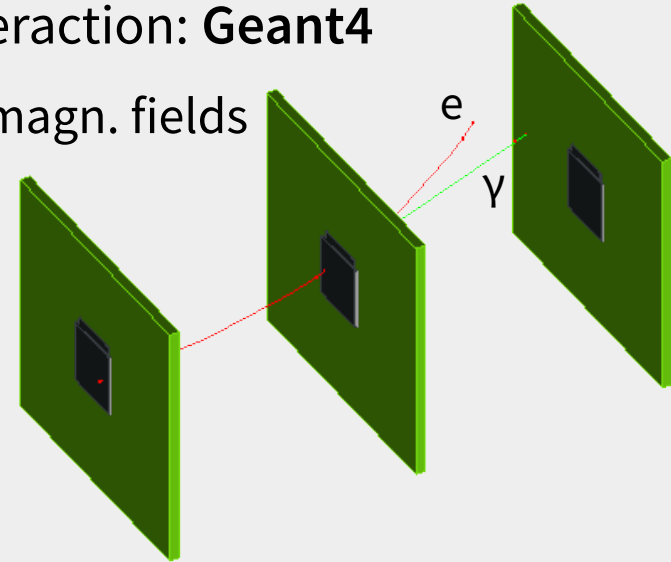
- Unlike in nature, in simulations we know everything
- Allpix² keeps history for all simulated objects – available for detailed analysis



Energy Deposition

- Using established software for simulating particle interaction: **Geant4**

- Tracking of particles through entire setup, including magn. fields
- Production and tracking of secondary particles
- Provides MC truth information on all particles
- Allows visualization of setup



- Possible alternatives:

- Very simple model: Depositing charge at single point or along line
- Custom code using energy loss spectra and lookup tables delta ray ranges
- Custom code for simulation of laser measurements

Charge Transport

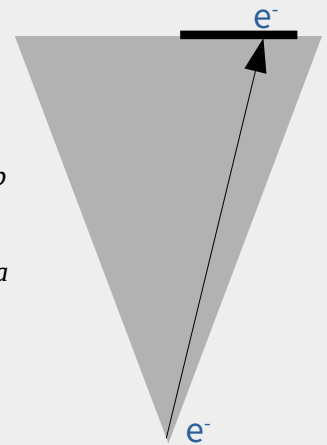
- Most crucial (and time consuming) component in simulation chain
- Various models with different complexity:
 - $O(1)$ – Projecting Charge Carriers
 - $O(N)$ – Integration of Equations of Motion
 - $O(2 \times N \times M)$ – Induced Signal at Electrodes
- Multiple charge carriers from same energy deposit propagated together
 - Depending on initial statistics and required accuracy
 - Some models allow to ignore electrons or holes
- Computing time given per group of charge carriers

O(1) – Projecting Charge Carriers

- With linear electric field, calculate approximate total drift time via analytical approximation of mobility integral
- For each (group of) charge carrier,
 - Calculate total drift time
 - Calculate total diffusion offset for this time
 - Put charge carrier on sensor surface, with offset drawn from Gaussian distribution of width σ_x
- Very fast simulation, few calculations
- Only works for linear electric field approximations (reasonable for many thick planar sensors) and without magnetic field

$$t = \int \frac{1}{v} ds \approx \frac{1}{u_0} \left[\frac{\ln(E(s))}{k} + \frac{s}{E_c} \right]_a^b$$

$$E(s) = ks + E_0$$

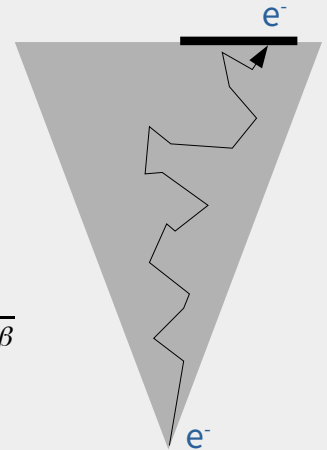


O(N) – Integration of Equations of Motion

- Successive integration of charge carrier motion
- Take each (group of) charge carrier
 - Calculate mobility μ from local electric (and magnetic) field (using Jacoboni/Canali parametrization)
 - Calculate velocity
 - Make step, add diffusion offset from Gaussian distribution
 - Repeat N times until sensor surface is reached
- Using 5th order Runge-Kutta-Fehlberg method
 - Adaptive step size according to position uncertainty
 - Method allows description of drift in complex field configurations

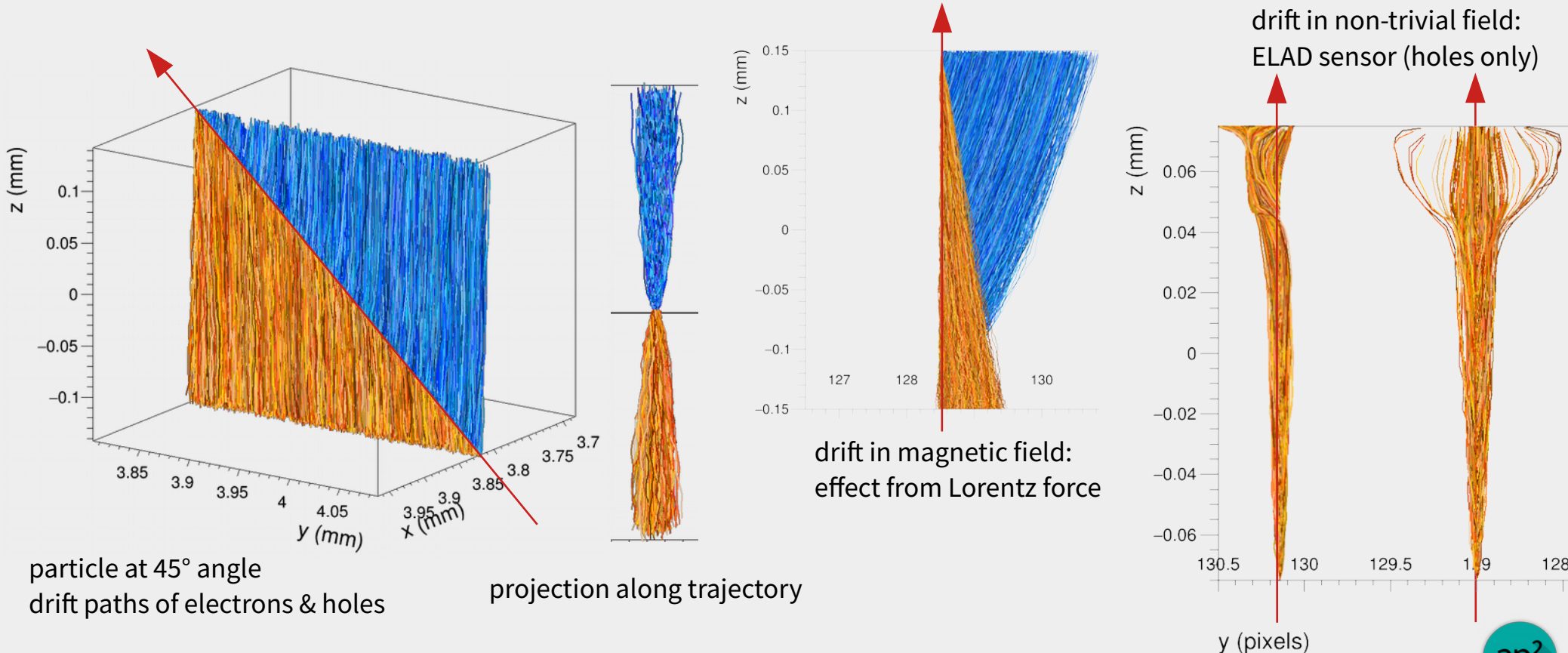
$$\mu = \frac{v_m}{E_c} \frac{1}{(1 + (E/E_c)^\beta)^{1/\beta}}$$

$$\sigma_x = \sqrt{\frac{2k_b T}{e} \mu t}$$



Drift Path Visualizations

Recording individual steps of the RKF integration to produce visualizations



particle at 45° angle
drift paths of electrons & holes

projection along trajectory

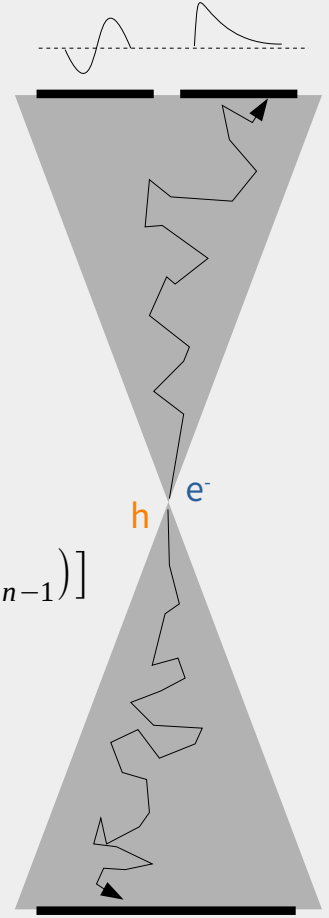
drift in magnetic field:
effect from Lorentz force

drift in non-trivial field:
ELAD sensor (holes only)

O(2xNxM) – Induced Signal at Electrodes

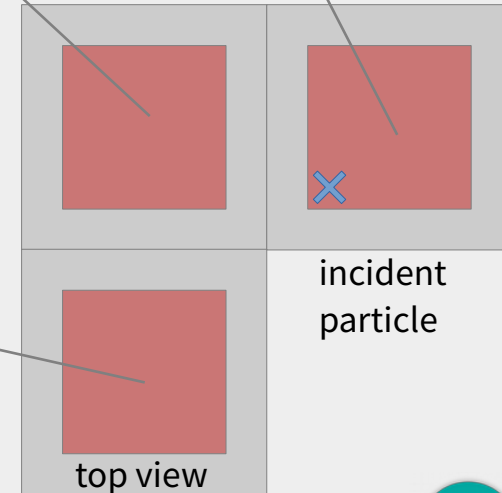
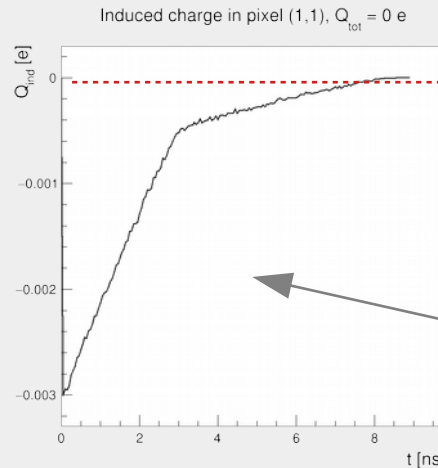
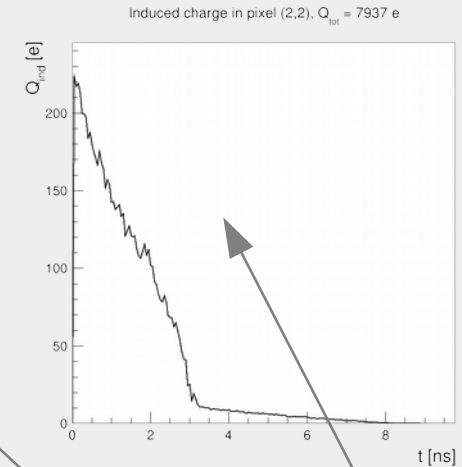
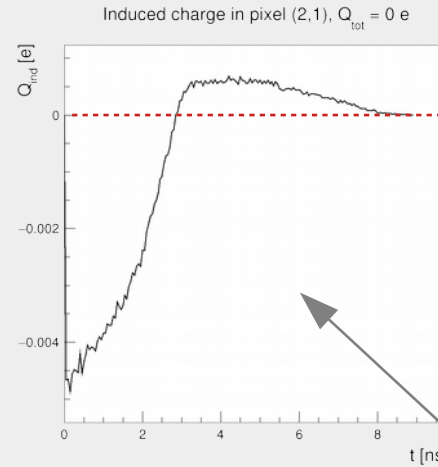
- Successive integration of motion, calculating induced charge per step
- Take each (group of) charge carrier
 - Calculate mobility & velocity from local fields
 - Make step, add diffusion offset from Gaussian distribution
 - Get induced charge from weighting potential difference for M neighbors
 - Repeat N times until sensor surface is reached
- Allows time-resolved simulation
 - Requires weighting potential, might not be trivial to obtain
- Time consuming:
 - Calculation for all neighboring electrodes for every step
 - Requires propagating both electrons and holes (x2)

$$Q_n^{ind.} = \int_{t_{n-1}}^{t_n} I_n^{ind.} dt = q [\phi(x_n) - \phi(x_{n-1})]$$



Current Pulses at Electrodes

- Example of transient simulation released in Allpix Squared 1.4
- Detector with
 - 300 μm x 300 μm pitch,
200 μm x 200 μm electrodes,
100 μm sensor thickness
 - MIP-equiv. Particle,
80 e/h-pairs / μm
- Struck pixel sees total charge
- Neighbor pixels see tiny pulses,
net charge is zero

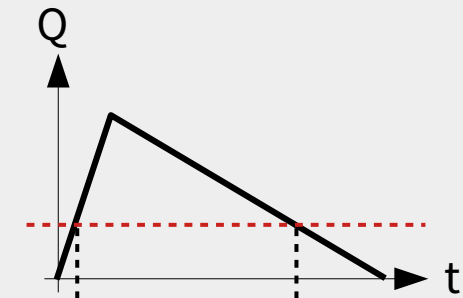
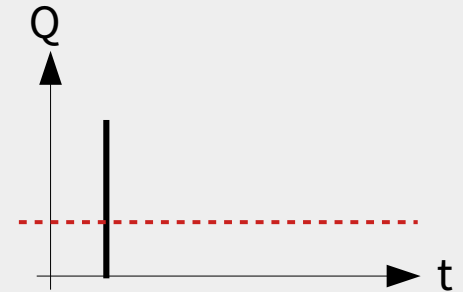


Including Additional Effects

- Depending on simulation scenario, additional effects might be required
 - Slow sensors might expose effects from recombination
 - Irradiated sensors see strong effect from trapping
- Some can be added ad-hoc to propagation models:
 - Trapping of carriers (stop propagation for certain time)
 - Recombination (stop propagation completely)
 - Multiplication (create new charge carriers at strong electric fields)
- Other effects (shielding effects in electric field, charge carrier self-interaction) are more difficult to include, complexity might go beyond MC simulations

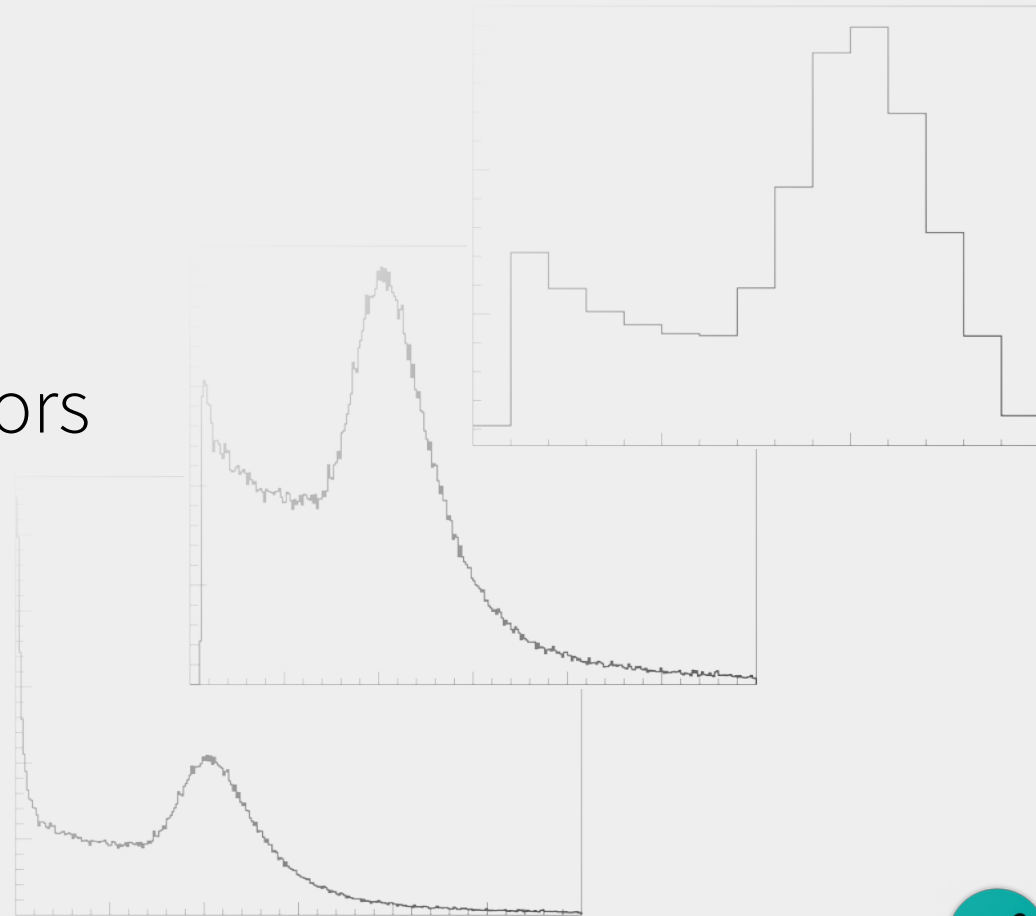
Digitization

- Methods depend on available information from charge transport:
- Simple front-end
 - Compare total charge against configured threshold
 - Add input noise, threshold dispersion, convert to ADC units
- Front-end with timing capabilities
 - Requires current pulse
 - Threshold crossings for time-of-arrival and time-over-threshold
- Full front-end simulation
 - Requires current pulse shape
 - Lookup tables for front-end response function, produced from device simulations



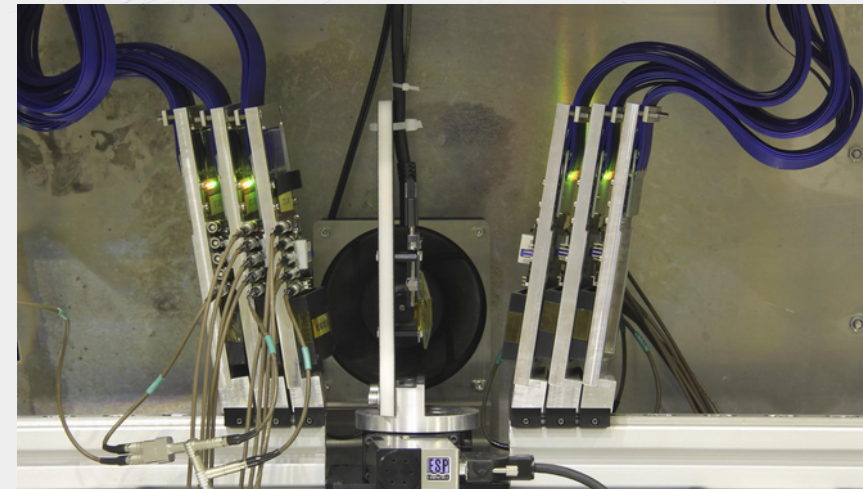
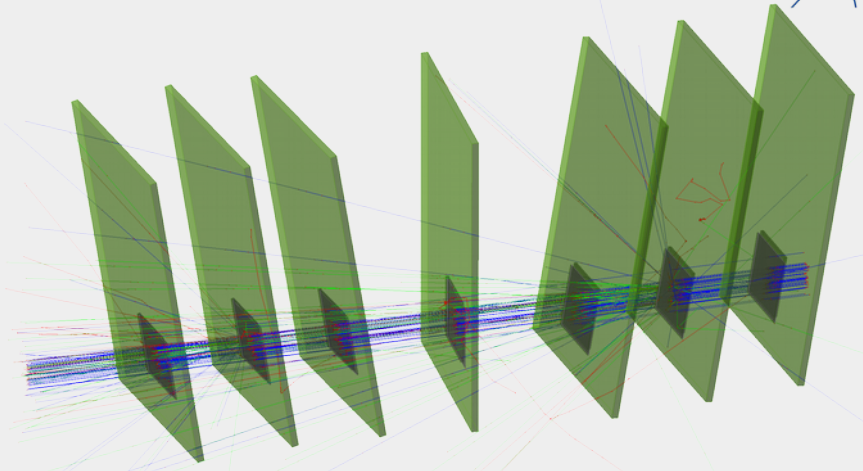
Examples

Planar, ELAD and CMOS Sensors



Simulation of Detector System

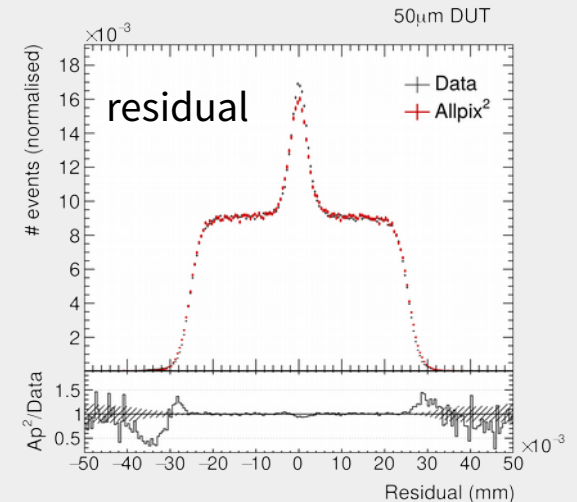
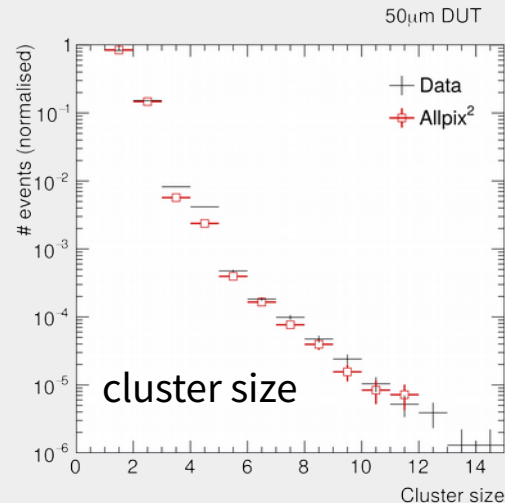
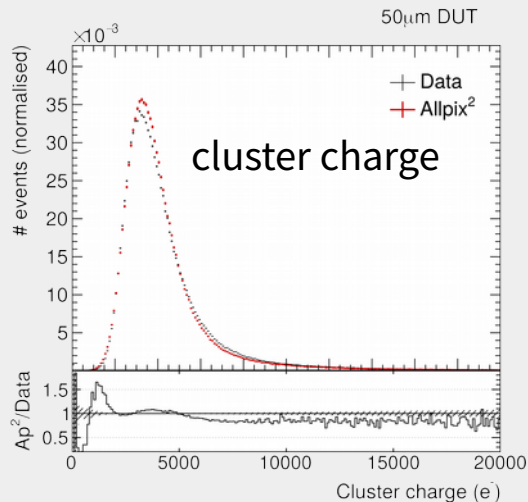
- Simulation of a beam telescope setup:
CLICdp Timepix3 telescope @ SPS H6
 - Telescope: 6x Timepix3 w/ 300 μm sensors
 - DUT: 1x Timepix3 w/ 50 μm sensor
- Validation of reconstruction
- Different algorithms used:
 - Telescope: projection
 - DUT: successive integration
- Linear electric field approximation



NIMA 901 (2018) 164 – 172
[doi:10.1016/j.nima.2018.06.020](https://doi.org/10.1016/j.nima.2018.06.020)

Simulation of Detector System

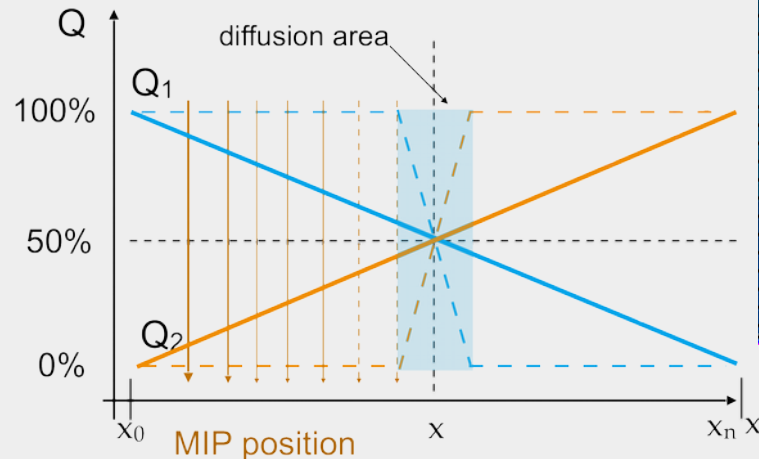
- Using same reconstruction algorithms as for data: clustering, η correction, tracking
- Very good agreement between data and simulation observed (total charge: **Geant4**; cluster size: both; residual shape: **Allpix²**)



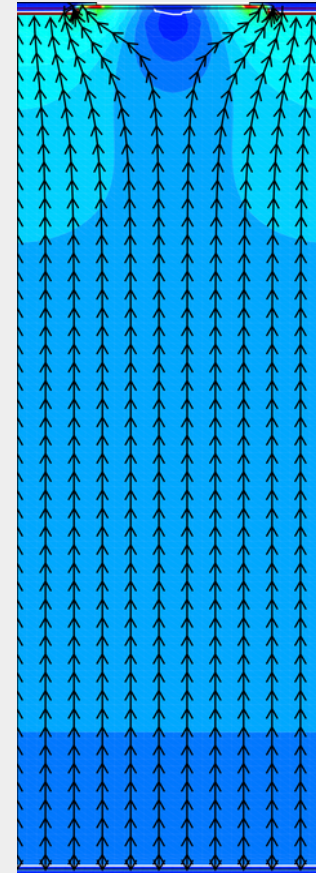
Enhanced Lateral Drift Sensors

- Resolution in **thin sensors** limited to $\text{pitch} / \sqrt{12}$
- **Enhance charge sharing** via electric field
 - Deep implants create lateral field
 - Spread of charges during drift, cluster size ~ 2
- Theoretical optimum: linear sharing

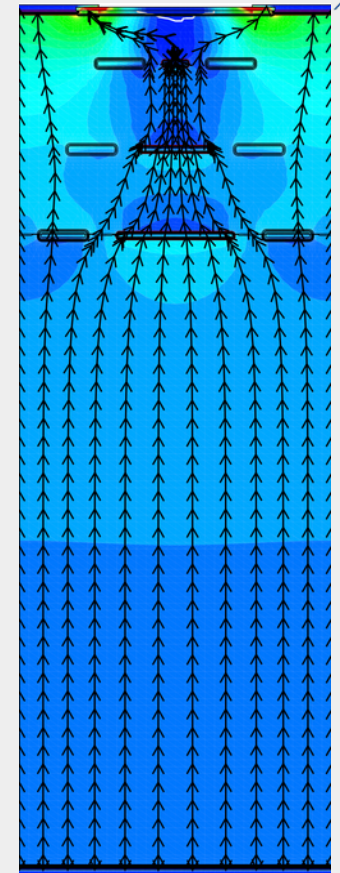
- No prototype yet:
use simulation to optimize sensor



standard planar



p-ELAD

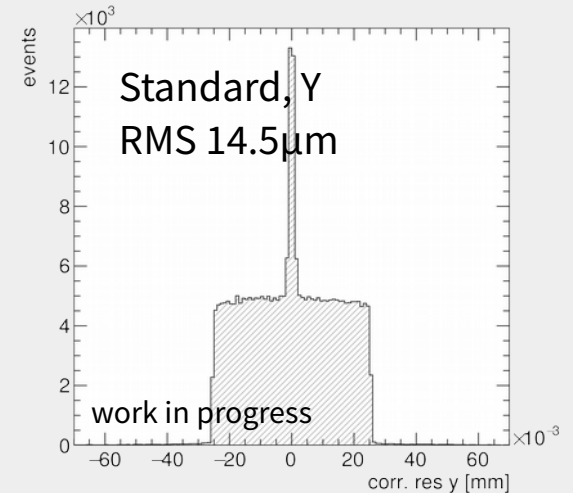
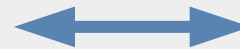
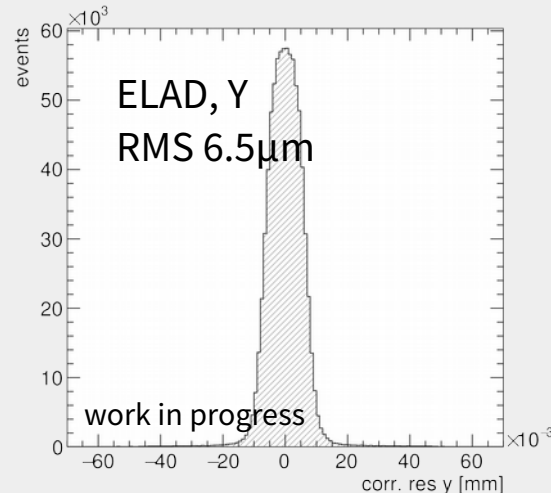
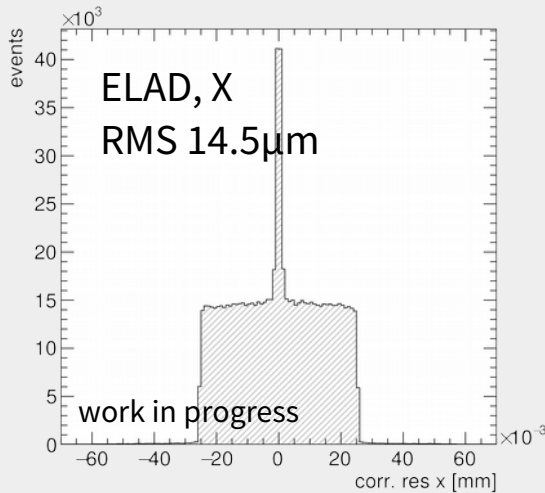
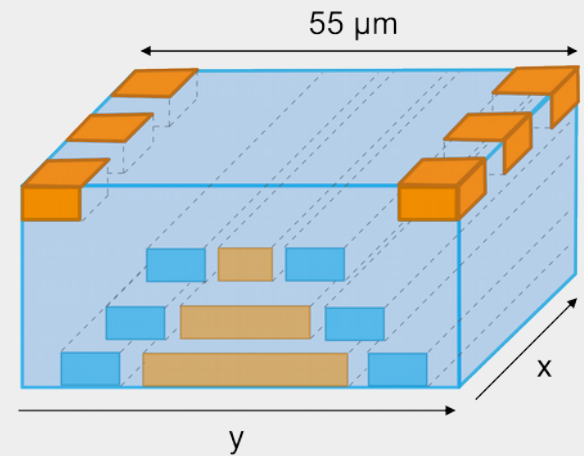


NIMA 831 (2016) 242 – 245
[doi:10.1016/j.nima.2016.01.092](https://doi.org/10.1016/j.nima.2016.01.092)

Enhanced Lateral Drift Sensors

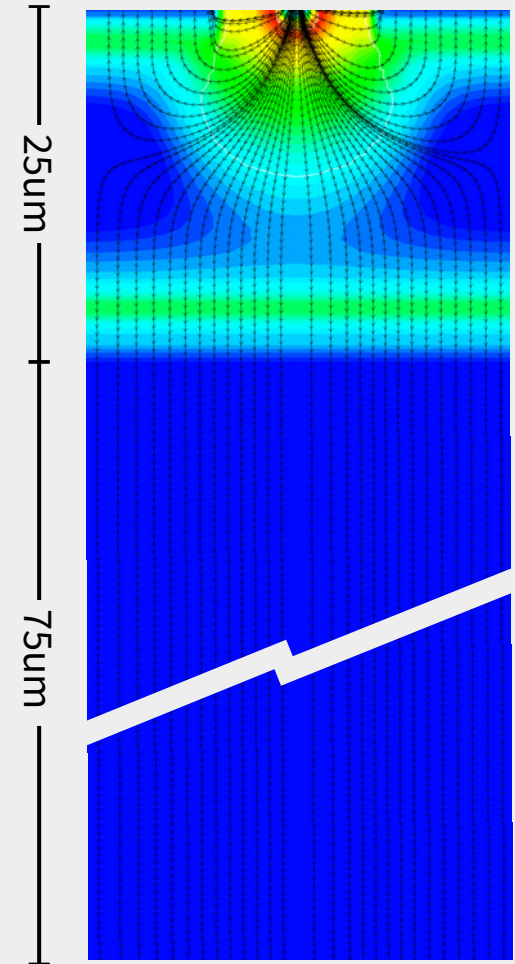


- MC Simulation with Timepix3 pitch: $55\ \mu\text{m}$
- Strip-like ELAD implants, expecting
 - X: Unaffected charge sharing along strip implants
 - Y: Stronger charge sharing across strip implants
- Using TCAD electric field & successive integration model



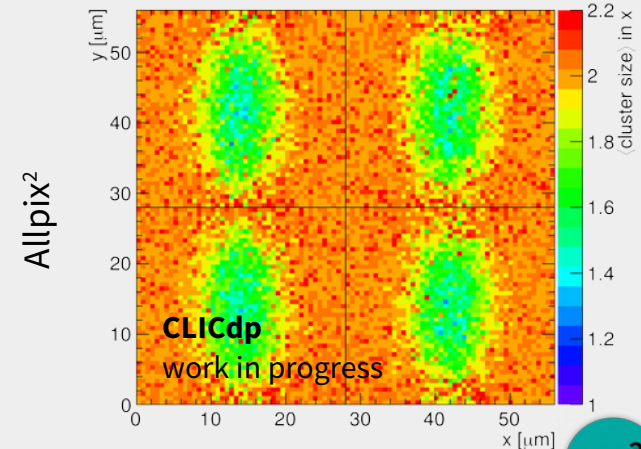
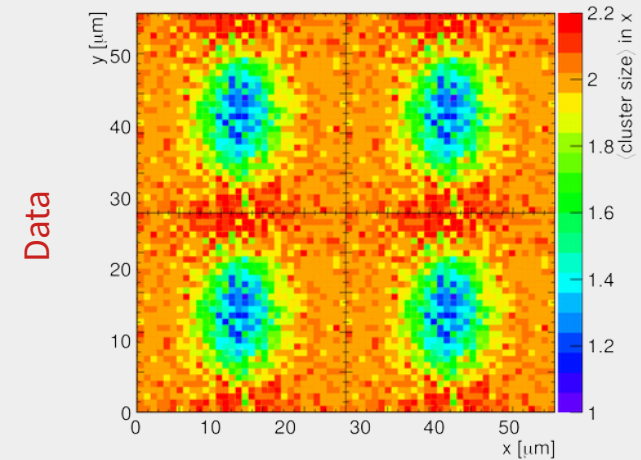
Monolithic CMOS in High-Resistivity Silicon

- ALICE Investigator chip, pixels with 28x28um pitch
 - Field in top 25um (high-resistivity) silicon
 - Undepleted in 75um silicon substrate
 - Measurements published: [doi:10.1016/j.nima.2019.02.049](https://doi.org/10.1016/j.nima.2019.02.049) NIMA 927 (2019) 187-193
- Simulation compared to data from SPS, 120 GeV π
 - Simulating only detector under investigation
 - Using Monte Carlo truth information as reference
 - Smearing with telescope resolution obtained from data
- Electrostatic field obtained from TCAD simulations



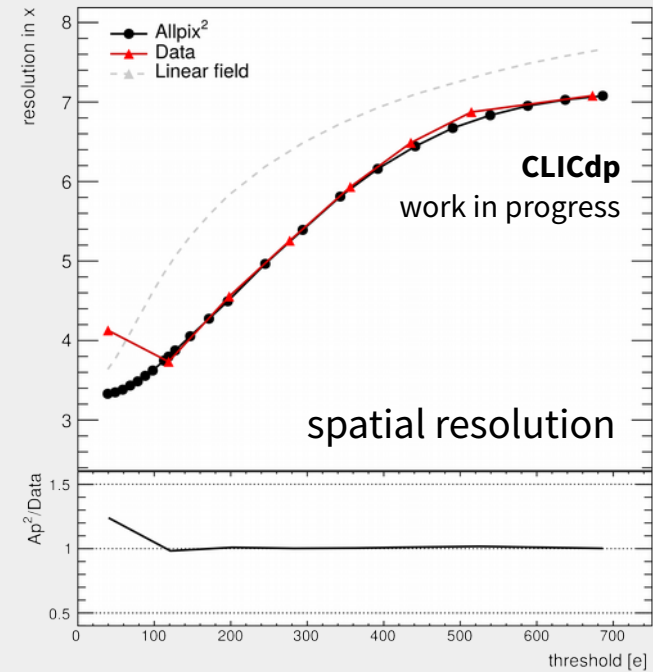
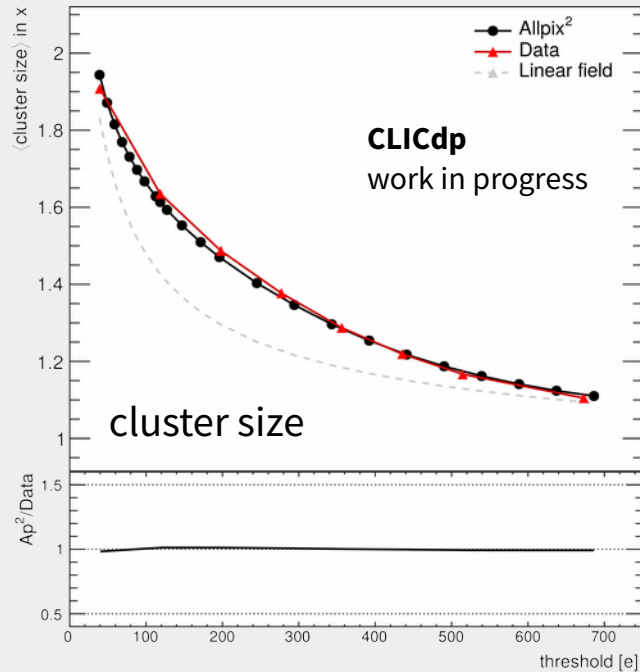
Monolithic CMOS in High-Resistivity Silicon

- High statistics of 3D Monte Carlo simulation:
 - Sampling of quantities within pixel cells
 - Here: cluster size in x
- Fully depleted planar sensors: expecting bands without y-dependence
- Cluster size exhibits correlation between x/y
 - Reason is field configuration & signal contributions from diffusion
 - Simulation with TCAD electric field reproduces correlation

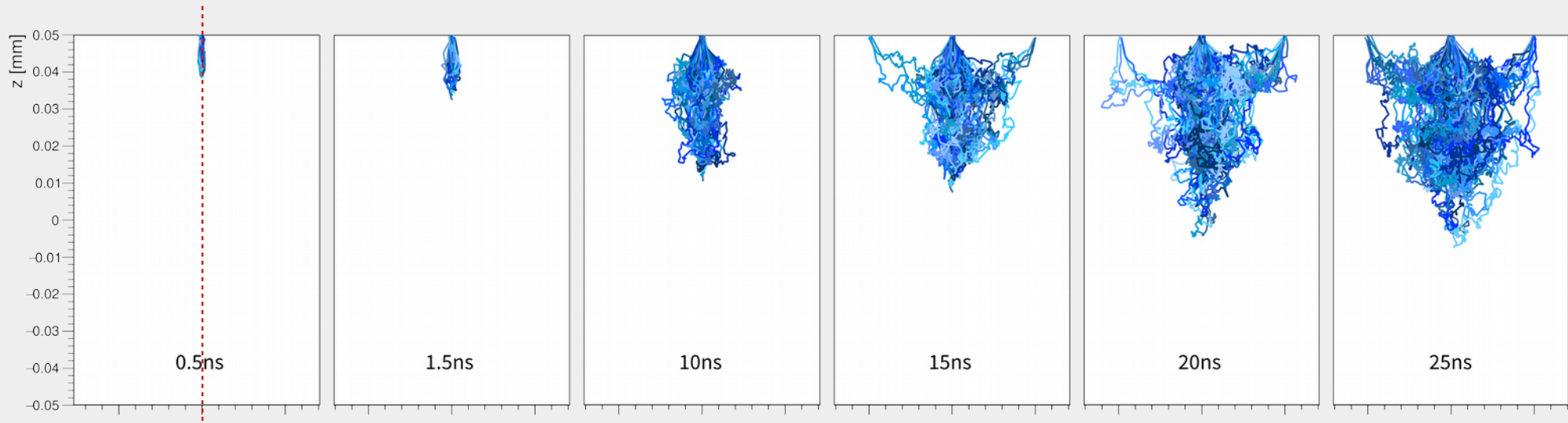


Reproducing Resolution at Different Thresholds

- Data and simulation match well, e.g. for **cluster size & resolution vs. threshold**
- Simulation with linear electric field does not describe data



Visualizing Charge Carrier Motion



- Charge carrier movements at different times after the deposition
 - Only electrons shown which reach the electrodes, holes & other electrons omitted
 - Contributions from the substrate silicon after ~ 10 ns
 - Charge sharing visible after ~ 15 ns

A Word on Writing Code for MC Simulations

- Implementation of algorithms is not the most time-consuming part
- Most time-consuming part is to do it such, that the algorithms are...
 - ...validated with prototype data & device simulations
 - ...well documented
 - ...maintainable over a period longer than O(1 fellow) / O(1 PhD)
- Development of Allpix²: spend considerable time on
 - Writing documentation → lower barrier for new users
 - Implementing automated testing, compilation → ensure software always works
 - Code review for new features → ensure functionality/compatibility

User Manual & Code Documentation

- Focus from the very beginning on well-documented framework
- Source code documentation for every class, method
 - Doxygen markup for code reference
 - Deployed to the website for tags
- Extensive User Manual in LaTeX
 - Automatically compiled by CI
 - Module documentation as Markdown
 - Document module parameters, algorithms
 - Included in manual via Pandoc

```
namespace allpix {  
  
    /**  
     * @brief Instantiation of a detector mode  
     *  
     * Contains the detector in the world with  
     * (like the electric field). All model sp  
     * properties are stored in its DetectorMo  
     */  
    class Detector {  
        friend class GeometryManager;  
  
    public:  
        /**  
         * @brief Constructs a detector in the  
         * @param name Unique name of the dete  
         * @param model Model of the detector  
         * @param position Position in the wor  
         * @param orientation Rotation matrix  
         */  
        Detector(std::string name,  
                std::shared_ptr<DetectorModel>  
                ROOT::Math::XYZPoint position  
                const ROOT::Math::Rotation3D&  
  
        /**  
         * @brief Get name of the detector  
         * @return Detector name  
         */  
        std::string getName() const;
```

GenericPropagation

Maintainer: Koen Vanders (k.vanders@cern.ch), Simon Spannagel (s.spannagel@cern.ch)

Status: Functional
Input: DepositedCharge
Output: PropagatedCharge

Description

Simulates the propagation of electrons and holes through the sensitive sensor volume of the detector. It allows to propagate sets of charge carriers together in order to speed up the simulation while maintaining the required accuracy. The propagation process for these sets is fully independent and no interactions are simulated. The maximum size of the set of propagated charges and thus the accuracy of the propagation can be controlled.

The propagation consists of a combination of drift and diffusion simulation. The drift is calculated using the charge carrier velocity derived from the charge carrier mobility parameter μ , and the electric field E . The carrier mobility for other electrons or holes is automatically chosen based on the type of the charge carrier under consideration. Thus, also type with both electrons and holes is treated properly.

The two parameters `propagate_electrons` and `propagate_holes` allow to control which type of charge carrier is propagated to their respective electrodes. Other sets of the carrier types can be selected, or both can be propagated. It should be noted that this will slow down the simulation considerably, since twice as many carriers have to be handled inside. It should only be used where sensible. The direction of the propagation depends on the electric field configuration, and should be simulated the carrier types selected are actually transported to the endpoint side for low electric fields, a warning issued if a possible misconfiguration is detected.

A fourth-order Runge-Kutta-Fehlberg method with fifth order error estimation is used to integrate the electric field. After every Runge-Kutta step, the diffusion is accounted for by applying an offset drawn from a Gaussian distribution calculated from the Einstein relation:

$$r = \sqrt{\frac{2D \Delta t}{3}}$$

using the carrier mobility μ , the temperature T and the time step. The propagation stops when the set of charges reaches any of the electrodes.

The propagation module also produces a variety of output plots. These include a 3D trajectory of the path of all separately propagated charge carrier sets from their point of deposition to the end of their drift, with nearby paths having different colors. In the coloring scheme, electrons are marked in blue colors, while holes are presented in different shades of orange. In addition, a 2D GC simulation for the drift of all individual sets of charges (with the size of the point proportional to the number of charges in the set) can be produced. Finally, the module produces 2D contour animations in all the planes normal to the X, Y and Z axis, showing the concentration flow in the sensor. It should be noted that generating the animations is very time-consuming and should be switched off, even when debugging drift behavior.

Dependencies

This module requires an installation of Digesit.

Parameters

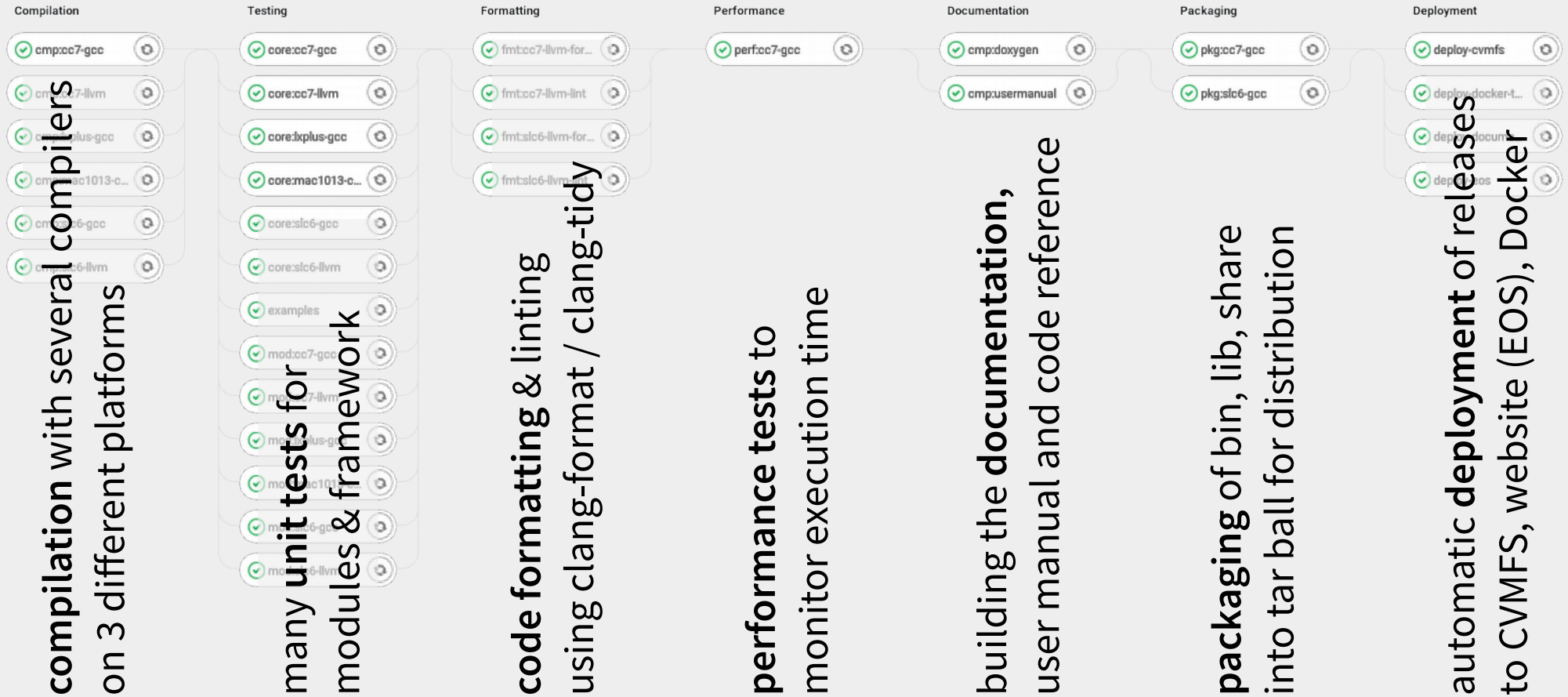
- `temperature`: Temperature of the sensitive device, used to estimate the diffusion constant and therefore the strength of the diffusion. Defaults to room temperature (293.15K).
- `charge_per_step`: Maximum number of charge carriers to propagate together. Controls the total number of deposited charge carriers at a specific point in time and the number of charge carriers used, with the remaining charge carriers. A value of 10 charges per step is usually default if this value is not specified.
- `spatial_precision`: Spatial precision to use for. The accuracy of the Runge-Kutta propagation is adjusted to reach this spatial precision after calculating the necessary from the fifth order error method. Defaults to 0.1 cm.
- `time_step_start`: Time step to initiate the Runge-Kutta integration with. An aggressive estimation of the parameter reduces the time to estimate the time step to the spatial precision parameter. Default value 0.01 ns.
- `time_step_min`: Minimum step time to use for the Runge-Kutta integration regardless of the spatial precision. Defaults to 5 ps.
- `time_step_max`: Maximum step time to use for the Runge-Kutta integration regardless of the spatial precision. Defaults to 0.1 ns.
- `integration_order`: Time with which charge carriers are propagated. After exceeding this time, no further propagation is performed for the respective carriers. Defaults to the LHC bunch crossing time of 25 ns.
- `propagate_electrons`: Select whether electron type charge carriers should be propagated to the electrodes. Defaults to false.
- `propagate_holes`: Select whether hole-type charge carriers should be propagated to the electrodes. Defaults to false.
- `output_plots`: Determine if output plots should be generated for every event. This causes a significant slowdown of the simulation. It is not recommended to enable this option for runs with more than a couple of events. Default is false.
- `output_plots_line`: True to generate line plots. The amount of points plotted indirectly determines the amount of points plotted. Defaults to reverse, true if not explicitly specified.
- `output_plots_theta`: Viewport angle of the 3D animation and the 2D line graph around the world Z-axis. Defaults to zero.
- `output_plots_phi`: Viewport angle of the 3D animation and the 2D line graph around the world X-axis. Defaults to zero.
- `output_plots_use_pixel_units`: Determine if the plots should use pixels as unit instead of metric length scales. Defaults to false (i.e. using the metric system).
- `output_plots_use_equal_scaling`: Determine if the plots should be produced with equal distance scales on every axis (if this implies that some points will fall out of the graph). Defaults to true.
- `output_plots_align_plots`: Determine if the plot should be aligned on pixels. Defaults to false if enabled the start and the end of the axis will be at the right place between pixels.
- `output_animations`: In addition to the other output plots, also write a GC animation of the charges drifting towards the electrodes. This is very slow and writing the animation takes a considerable amount of time, therefore defaults to false. This option also requires `output_plots` to be enabled.
- `output_animations_line_scaling`: Scaling for the animation used to convert the actual simulation time to the time step the animation. Defaults to 1:1, meaning that every conversion of the simulation requires an animation of a single second.
- `output_animations_marker_size`: Scaling for the markers on the animation. Defaults to one. The markers are already internally scaled to the charge of the step, normalized to the maximum charge.
- `output_animations_color_equal_scaling`: Scaling to use for the color scale axis from the theoretical maximum charge at every single plot step. Default is 1:1, meaning that the maximum of the color scale axis is equal to the total amount of charges. Defaults to false (i.e. the axis is not scaled). Parameter can be used to improve the color scale of the output plots.
- `output_animations_color_markers`: Determine if colors should be for the markers in the animations. Defaults to false.

Usage

An example of generic propagation for all sensors of type "Trapez" at room temperature using packets of 25 charges in the following:

```
{GenericPropagation  
  type = "Trapez"  
  temperature = 293K  
  charge_per_step = 25
```

Continuous Integration & Testing



Code Review via Merge Requests

- No new code lands in master without review by another party
 - Using GitLab's approval feature
 - Extensive discussions about code, but also style, naming schemes
- Proven to be **very effective**
 - Several bugs found before the merge
 - New users appreciate guidance
- Proven to be **labor-intensive**
 - Read (and understanding) every change
 - Always be supportive, positive

...just some of them

Python macro to read output objects TTree !191 · opened 2 months ago by Sebastien Murphy	MERGED ✓ 18 updated 1 week ago
Revamp MeshConverter: Change interpolation & improve performance !200 · opened 3 weeks ago by Simon Spannagel	MERGED ✓ 5 updated 1 week ago
Write full Proteus configuration in RCEWriter !203 · opened 2 weeks ago by Moritz Kiehn	MERGED ✓ 12 updated 1 week ago
Invert Detector Rotations !164 · opened 6 months ago by Simon Spannagel documentation detector models bug	MERGED ✓ 8 updated 2 weeks ago
RCEWriter: fix Proteus geometry output !202 · opened 2 weeks ago by Moritz Kiehn	MERGED ✓ 3 updated 2 weeks ago
FieldParser: be more careful about units !201 · opened 3 weeks ago by Simon Spannagel	MERGED ✓ 1 updated 2 weeks ago
Add option for a depletion from the backplane !198 · opened 3 weeks ago by Paul Schutze physics improvement	MERGED ✓ 11 updated 3 weeks ago
New Field File Format APF & common FieldParser/FieldWriter !197 · opened 1 month ago by Simon Spannagel	MERGED ✓ 11 updated 3 weeks ago
New Module: DepositionPointCharge !194 · opened 1 month ago by Simon Spannagel	MERGED ✓ 12 updated 1 month ago

Allpix² Users, Contributors



- First **user workshop** held
26-27 November 2018 @ CERN
Tutorials, discussions, feedback
- Increasing number of community contributions to the code base

ONERA Aerospace Lab, Toulouse
Georg-August-Universität Göttingen
University of Birmingham
University of California, Berkeley
NIKHEF, Amsterdam
University of Glasgow
Czech Techn. University, Prague
Rutherford Lab, STFC
ETH Zurich
IHEP Beijing
Freiburg University
Utrecht University
CLICdp @ CERN
CMS Pixel @ CERN
ATLAS Strips @ CERN
LHCb VeloPix @ CERN
ATLAS Monolithic @ CERN
ATLAS @ DESY
CMS Lorentz Angle @ DESY
ELAD @ DESY
University of Liverpool
ATLAS SCT @ KEK
Dortmund University
Université de Genève
AGH University Krakau
Université de Montréal
Charles University, Prague

Disclaimer: these are just some user groups we have been in contact with...

In a nutshell...



Summary

- Designing a new silicon detector is a major undertaking
- Simulations are a vital component of the prototyping effort
 - Device simulations help in understanding and optimizing the design
 - Monte Carlo Simulations are required to assess the device performance
- Models with different complexity are available
 - fast & coarse ↔ slow & precise
- Including results from device simulations improves detector modeling
- **Allpix Squared**: flexible platform for implementation of different algorithms
- Extensions planned, participation from community very welcome

Allpix Squared Resources



Website

<https://cern.ch/allpix-squared>



Repository

<https://gitlab.cern.ch/allpix-squared/allpix-squared>



Docker Images

https://gitlab.cern.ch/allpix-squared/allpix-squared/container_registry



User Forum:

<https://cern.ch/allpix-squared-forum/>



Mailing Lists:

allpix-squared-users <https://e-groups.cern.ch/e-groups/Egroup.do?egroupId=10262858>

allpix-squared-developers <https://e-groups.cern.ch/e-groups/Egroup.do?egroupId=10273730>



User Manual:

<https://cern.ch/allpix-squared/usermanual/allpix-manual.pdf>

